

### T3AWG3252 / T3AWG3352 Data Sheet

### **High Definition Dual Channel Arbitrary Waveform Generator**



#### **Accurate and Versatile Waveforms Generation**

- 16 Bit Vertical Resolution
   Exceptional signal fidelity for developing quality products with a reduced design cycle.
- 24 V<sub>pp</sub> Output Voltage and ±12 V HW Baseline Offset for a total output voltage window ±24 V or 48 V (50 Ohm into High Impedance)
- Unmatched wide output voltage window enables generating challenging in amplitude large-signal waveforms.
- Waveform memory up to 1 Gpoint @Ch
- Unmatched deep memory depth allows to store and reproduce complex pseudo-random waveforms for long play time testing.

Mixed Signal Generation

Combining the 2 analog channels with 8 synchronized Digital Channels for debugging and validating digital design.

 Multifunctional solution instrument (AFG/AWG/DPG) Arbitrary Function Generator, Arbitrary Waveform Generation and Digital Pattern Generation functionalities combined into one instrument.

Standard warranty is one year.

#### **Key Specifications**

Model	T3AWG3252	T3AWG3352	
Frequency Range (Sinewave, AFG mode)	1 μH to 250 MHz	1 μH to 350 MHz	
Sample Rate (AWG mode, not interpolated)	1.0 GS/s	1.2 GS/s	
Vertical Resolution	16 Bits		
Memory	Up to 1 Gpoint/Ch.		
Output Voltage V <sub>pp</sub> (peak to peak)	12 V <sub>pp</sub> (50 Ohm into 50 Ohm), 24 V <sub>pp</sub> (50 Ohm into High-Impedance)		
Digital Pattern Generator (DPG)	8 Channels @ 1.0 Gbps 8 Channels @ 1.2 Gbps		

#### **AFG Operational Mode**

- Improved Direct Digital Synthesis (DDS) based technology
- Fixed sampling clock



Arbitrary Function Generation (AFG functionality)

#### **AWG Operational Mode**

- Variable Clock True-Arbitrary Technology
- Variable Sampling Clock
- Mixed Signal Generation: 2 Analog Channels and 8 Digital Channels



Arbitrary Waveform Generation (AWG functionality)



Digital Pattern Generation (DPG functionality)

### A multifunctional generator with an innovative architecture

T3AWG3352-3252 are multifunctional generators that combines many functions in one instrument, including Arbitrary Function Generator, Arbitrary Waveform Generator and Digital Pattern Generator.

These three-different functionalities are leveraging on the HW flexibility adopting two different technologies.

An improved Direct Digital Synthesis (DDS) based technology adopted when using the Function Generator (AFG) lets the user to change glitch free on-the-fly all the parameters preserving the waveform shape.

All control and setting are always one touch away: swipe gesture to change the channel, the carrier selection and have access to the modulation parameters, swipe into the waveform gallery to import a signal at a glance and use the touch-friendly virtual numeric keyboard to change parameters values.

The variable clock, true-arbitrary technology adopted when using the Arbitrary Waveform / Digital Pattern Generator lets the user to create complex waveforms of analog and digital pattern, insert them is a sequence, apply loops, jumps and conditional branches. Digital output combined and synchronized with analog output

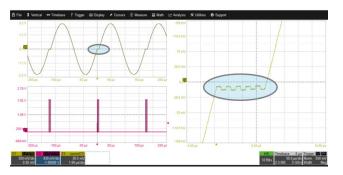
signals represents an ideal tool to troubleshoot and validate digital design.

The waveform memory length of 128 Mpoints (up to 1 Gpoints optional) on each channel combined with number of waveforms entries up to 16,384 and the waveform repeat count higher then 4 10<sup>9</sup> or infinite make the T3AWG3252 and the T3AWG3352 the best-in-class waveform generators for the most demanding technical applications.

This disruptive and innovative hardware architecture provides the possibility to generate unmatched performances, versatile functionality, outstanding usability, making the T3AWG3352-3252 the ideal generator for today's and tomorrows test challenges.



### Exceptional Signal Fidelity with 16-bit Vertical Resolution



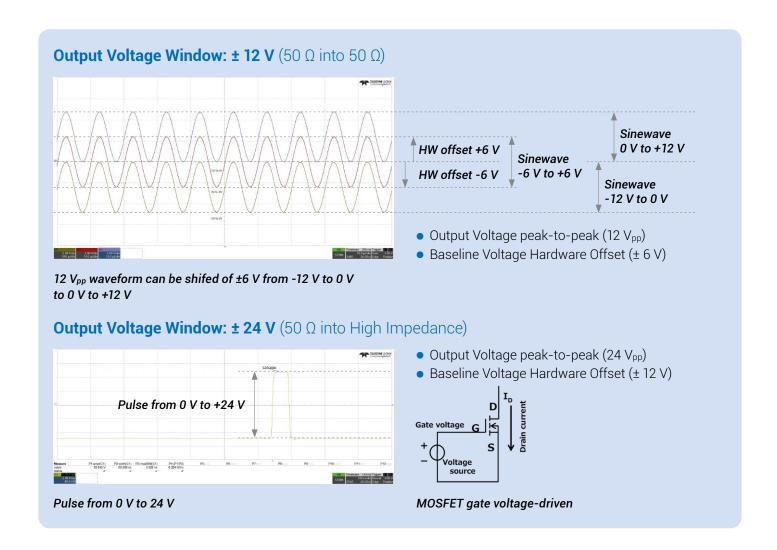
4V<sub>pp</sub> Sine Wave and 5 x 10 mV<sub>pp</sub> Square Wave Sequencing

Highest signal accuracy and precise waveform details generation are key contributors for developing quality products with a reduced design time. Indeed, the pressure is to get products to market faster with a shortest design cycle and with the increase of the quality goals. The exceptional Signal Fidelity of the T3AWG3352 and

T3AWG3252 with the 16-bit Vertical Resolution give the capability to emulate the thinnest details of your waveform making your testing highly efficient and increasing the confidence in your results as more stable and reliable.

### **Output Voltage Window ± 12 V** (50 $\Omega$ into 50 $\Omega$ ) **or ± 24 V** (50 $\Omega$ into High Impedance)

Output voltage swing is a compulsory requirement for key applications for the IC and Semiconductor Test or Defense marker segment. The T3AWG3252 and T3AWG3352 generators have unmatched outstanding voltage swing capability leveraging on two different combined features. The  $12\,V_{pp}$  (50  $\Omega$  into 50  $\Omega$ ) amplitude range and the  $\pm 6\,V$  (50  $\Omega$  into 50  $\Omega$ ) hardware offset voltage. The following images show a  $12\,V_{pp}$  sinewave (50  $\Omega$  into 50  $\Omega$ ) shifted from -12 V to 0 V to 0 V to +12 V using the hardware base voltage offset setting and a  $24\,V_{pp}$  pulse from 0 V to  $24\,V$  (50  $\Omega$  into high Impedance).



#### **High Definition Stimulus-Response model:**

Applying an HD Stimulus with the T3AWG generator to the DUT and analysing the Response using an HD Oscilloscope Different measurements scenarios:

- **a.** Emulation of clean and "perfect signal", so that uncontrolled and unknown distortions are not influencing the DUT response behavior.
- **b.** Emulation of "real-world signal" including distortions to test the DUT response behavior before any signal source is available. Playback of signals previously acquired using the oscilloscope and imported into the AWG.
- **c.** Emulation of extreme signal condition "stress test", we can emulate difficult conditions and corner case signals that can be statistically infrequent to test the DUT response behavior.
- **d.** Emulation of noise or interference signal "noise and interference immunity", so we can generate expected interference signal to add to expected signal and test the DUT response behavior.



HD AWG (stimulus)

**Device Under Test (DUT)** 

HD scope (response)

# Accurately emulate the thinnest waveform details at largest output voltage swings

High Definition T3AWG3352-3252 generators are very powerful and ideal tools for all the High Definition stimulus-response testing scenarios.

There are situations when you want to generate an "ideal signal" to test your device when uncontrolled and unknown distortions are not influencing the behavior of your device.

Alternatively, you may want to test your device with a "real-world signal" previously acquired with the

oscilloscope, imported into the HD arbitrary waveform generator and then played-back for all the time needed comfortably testing your device in the lab. Often real-world signals can be accessible to be acquired with an HD oscilloscope only for very short time or in difficult environmental situation like for high energy physics or aero-space applications. This makes impossible to do any design of your device at the place where the real-world signal can be sourced, then the HD arbitrary waveform generator provides an essential indispensable solution.

All the new emerging technologies and applications are requiring verifying the operating margin of your device emulating worst-case and infrequent corner-case conditions.

Your device needs to be tested to its performance limit and "stress test" during the product development is vital to avoid the risk of any device malfunction your customer ends up finding.

The High Definition T3AWG3352-3352 generators are ideal for precisely generating degraded or stressed signals thanks to the capability to emulate accurately any waveform details because of the 16-bit vertical resolution and in addition to emulate large voltage swings because of the 12  $V_{pp}$  combined with the  $\pm$  6 V HW Voltage baseline.

High Definition T3AWG3352-3252 have unmatched output voltage window  $\pm 24$  V, 48 V in case of 50  $\Omega$  into High Impedance or  $\pm 12$  V, 24 V in case of 50  $\Omega$  into 50  $\Omega$ .

Definitively you want your device properly working when in the presence of signals or noise interfering.

Today's technology density, co-existing of many communications systems, highest standard in product reliability make a must to go for "noise and interference immunity" testing.

The High Definition T3AWG3352-3352 generators are the perfect arbitrary generator for product noise susceptibility, interference immunity and EMI applications because of the excellent output signal spectral purity, the unmatched deep waveform memory enabling long play-time testing combined with versatile waveforms creation thanks to the intuitive and easy waveform sequencer user interface.

# Easily automate your test and measurement requirements by using the programming examples

#### Examples are available for both the Arbitrary Function Generator and Arbitrary Waveform Generator operating modes

T3AWG3252 and T3AWG3352 are easily added to your automated test environment. In addition to the programing manuals, which include the complete list of ASCII SCPI commands, programming examples are available for both the AFG (Function Generator) and AWG (Arbitrary Waveform Generator) operating modes.

These programming examples make it easy to connect to a powerful graphical programming environment like LabView™, take full advantage of the visualization and programming capabilities found in MATLAB™, or use the flexibility offered by PYTHON or the .NET programming languages.

The programming examples can be directly downloaded from the T3AWG product page of the Teledyne LeCroy website.

### High Definition Generator: Key Applications at a glance



Today's cars are including lots of highly sophisticated electronic control units (ECU) with very sensitive electronic components. The 16-bits vertical resolution combined with the 1.2 GS/s fast sampling rate make the High Definition T3AWG Arbitrary Generators indispensable tools for successfully and efficiency addressing the new testing challenges in automotive.

- CAN, CAN-FD, LIN, Flexray, SENT emulation and troubleshooting
- 100BASE-T1, 1000BASE-T1, BroadR-Reach emulation and immunity from interference signal and noise
- EMI debugging, troubleshooting and testing
- Electrical standards emulation up to 24 V
- Power MOSFET circuitry in automotive electronics optimization and characterization



Radar test and electronic warfare require to create specific complex true-to-life signals. The spectral purity, the wide voltage swing and the long waveform play-time make the High Definition T3AWG Arbitrary Generators the ideal tools for the military research and development sector.

- Frequency response, intermodulation distortion and noisefigure measurements characterization of components, subsystems and systems
- Phase Locked Loop (PLL) pull-in and hold range characterization
- RF I/Q modulators emulation and characterization
- RADAR base-band signals emulation to improve target resolution and detection and decrease false target return (noise immunity)
- MIL-1553, ARINC 429 and PRBS long-play time emulation



Researches and Scientists require to emulate pulses adding amplitude and timing variation imperfections in an accurate, detailed and repeatable controlled manner. Physics, electronics, chemistry, mechanics and other disciplines can benefit from the user interface versatility combined with the fast edge generation, the excellent dynamic range and the unmatched accuracy of the High Definition T3 AWG generators.

- Emulation of signal sources adding noise and known modulation distortion
- Modulating and driving laser diode with detailed waveform generation
- Generation/playback of real-world signals previously acquired using an High Definition Oscilloscope and imported into the High Definition T3 AWG generator.
- Emulation of long PRBS sequences with the 8 digital output channels synchronous with analog waveforms
- Generation of multi-level and multi-edge pulses long waveforms with the 1 GSample @Ch memory



Today's IC, components, electronic circuits and sensors are required to be highly reliable extending the operating range in many variables. Stress test need to be performed to confirm the mathematical model used for predicting breaking points or safe usage limits. The output voltage resolution combined with large voltage swing and the mixed mode operation make the High Definition T3AWG the best tool for developing quality components with a reduced design time.

- Clock generation for component overclock behavior and operating range limit and stress test
- Power Integrity testing of electric and electronic components for use in motor vehicles at low voltage
- Sensors signals generation: emulation of ideal signals or generation of real world signals after acquisition with an High Definition Oscilloscope.
- MOSFET gate drive amplitude signal emulation for MOSFET characterization and optimization
- Power up sequences of IC using the low impedance feature (5  $\Omega$  output impedance).

#### T3AWG3252 / T3AWG3352 High Definition Dual Channel Arbitrary Waveform Generators

#### **General Specifications**

	T3AWG3252	T3AWG3352
Number of Channels		
Analog	2	
Digital	0-8	
Markers	1	
Operating Modes		
AFG	Improved Direct Digital Synthes	izer (DDS) based technology
AWG	Variable Clock "True Arb" Techn	ology
Amplitude peak-to-peak		
Voltage Range $V_{pp}$ (50 $\Omega$ into 50 $\Omega$ )	0 to 6 V <sub>pp</sub> (12 V <sub>pp</sub> opt.)	
Accuracy <sup>1)</sup>	$\pm$ (1% of setting (V <sub>pp</sub> ) + 5 mV)	
Resolution	< 0.5 mV <sub>pp</sub> or 5 digits	
Output Impedance	Single-ended: 50 $\Omega$ and 5 $\Omega$ (Low Impedance)	
Amplitude HW Baseline Offset		
Range (50 $\Omega$ into 50 $\Omega$ )	-3 V to +3 V (-6 V to +6 V opt.)	
Range (50 Ω into High Impedance)	-6 V to +6 V (-12 V to +12 V opt.)	
Accuracy (50 Ω into 50 Ω)	±(1.0 %   setting   ± 5 mV)	
Resolution	< 4 mV or 4 digits	
Amplitude DC		
Amplitude Range (50 $\Omega$ , single-ended)	-3 V to +3 V (-6 V to +6 V opt.)	
Amplitude Accuracy	±(1.0 %   setting   ± 10 mV)	

 $<sup>^{1)}</sup>$  1 KHz Sine, 0 V offset, > 5 mVpp amplitude , 50  $\Omega$  load

## AFG Specifications Arbitrary Function Generator Operating Mode

#### **Waveform Types**

	T3AWG3252	T3AWG3352	
Ouput Channels	<u>'</u>	'	
Connectors	BNC on front panel		
Output Type	Single-ended		
Output Impedance	$50 \Omega$ or $5 \Omega$ (Low Impedance) sel	ectable	
General Specifications			
Technology	Direct Digital Synthesizer (DDS)		
Standard Waveforms	Sine, Square, Pulse, Ramp, Noise, DC, Sin(x)/x, Gaussian, Lorentz, Exponential Rise, Exponential Decay, Haversine		
Run Modes	Continuous, Modulation, Sweep, Burst		
Arbitrary Waveforms			
Vertical Resolution	16 bits		
Waveform Length	16.384 Points		
Internal Trigger Timer			
Range	13.3 ns to 100 s		
Resolution	104 ps		
Accuracy	±(0.1 % setting + 5 ps)		

	T3AWG3252		T3AWG3352	
Sine Wave Characteristics				
Frequency Range	1 μH to 250 MHz		1 μH to 350 MHz	
Frequency Resolution	1 μH or 15 digits		1 μH or 15 digits	
Output Amplitude (50 $\Omega$ into 50 $\Omega$ ) <sup>2)</sup>	0 to ≤ 70 MHz	12 V	0 to ≤ 70 MHz	12 V
	> 70 MHz to ≤ 120 MHz	9 V	> 70 MHz to ≤ 120 MHz	9 V
	> 120 MHz to ≤ 180 MHz	6 V	> 120 MHz to ≤ 180 MHz	6 V
	> 180 MHz to ≤ 250 MHz	3 V	> 180 MHz to ≤ 350 MHz	3 V
Flatness (1 V <sub>p-p</sub> , relative to 1 KHz)	DC to 250 MHz	± 0.5 dB	DC to 350 MHz	± 0.5 dB
Harmonic Distortion (1 V <sub>p-p</sub> ) typ.	1 μH to ≤ 10 MHz	< -65 dBc	1 μH to ≤ 10 MHz	< -65 dBc
	> 10 MHz to ≤ 50 MHz	< -55 dBc	> 10 MHz to ≤ 50 MHz	< -55 dBc
	> 50 MHz to ≤ 100 MHz	< -45 dBc	> 50 MHz to ≤ 100 MHz	< -45 dBc
	> 100 MHz to ≤ 125 MHz	< -40 dBc	> 100 MHz to ≤ 125 MHz	< -40 dBc
	> 125 MHz to ≤ 250 MHz	< -30 dBc	> 125 MHz to ≤ 350 MHz	< -30 dBc
Total Harmonic Distorsion (1 V <sub>p-p</sub> )	10 kHz to 20 KHz	< 0.1%	10 kHz to 20 KHz	< 0.1 %
Spurious (1 V <sub>p-p</sub> ) <sup>3)</sup>	1 μH to ≤ 10 MHz	< -60 dBc	1 μH to ≤ 10 MHz	< -60 dBc
	> 10 MHz to ≤ 250 MHz	< -55 dBc	> 10 MHz to ≤ 350 MHz	< -55 dBc
Phase Noise (1 V <sub>p-p</sub> , 10 KHz offset)	10 MHz	< -120 dBc/Hz typ.	10 MHz	< -120 dBc/Hz typ.
	100 MHz	< -115 dBc/Hz typ.	100 MHz	< -115 dBc/Hz typ.
Square Wave Characteristics				
Frequency Range	1 μH to 120 MHz		1 μH to 150 MHz	
Output Amplitude (50 $\Omega$ into 50 $\Omega$ ) <sup>2)</sup>	0 to ≤ 40 MHz	12 V	0 to ≤ 40 MHz	12 V
,	> 40 MHz to ≤ 80 MHz	10 V	> 40 MHz to ≤ 80 MHz	10 V
	> 80 MHz to ≤ 120 MHz	7 V	> 80 MHz to ≤ 150 MHz	7 V
Frequency Resolution	1 μH or 15 digits		1 μH or 15 digits	
Rise/Fall time (10 % to 90 %)	2.0 ns		2.0 ns	
Overshoot (1 V <sub>p-p</sub> )	< 2 %		< 2 %	
Jitter (rms)	< 20 ps		< 20 ps	
Pulse Wave Characteristics				
Frequency Range	1 μH to 120 MHz		1 μH to 150 MHz	
Frequency Resolution	1 μH or 15 digits		1 μH or 15 digits	
Output Amplitude (50 $\Omega$ into 50 $\Omega$ ) <sup>2)</sup>	0 to ≤ 5 MHz	12 V	0 to ≤ 5 MHz	12 V
,	> 5 MHz to ≤ 60 MHz	10 V	> 5 MHz to ≤ 60 MHz	10 V
	> 60 MHz to ≤ 120 MHz	7 V	> 60 MHz to ≤ 150 MHz	7 V
Pulse width	3 ns to (Period-3.0 ns)		2.5 ns to (Period-2.5 ns)	
Resolution	20 ps or 15 digits		20 ps or 15 digits	
Pulse duty cycle	0.1 % o 99.9 % (limitation o	of pulse width apply)	0.1% o 99.9 % (limitation o	of pulse width apply)
Leading/trailing edge transition time	2.5 ns to 1000 ns	1 11 37	2.0 ns to 1000 ns	1 11 37
Resolution	2 ps or 15 digits		2 ps or 15 digits	
Overshoot (1 V <sub>p-p</sub> )	< 2 %		< 2 %	
Jitter (rms, with rise time and	< 20 ps		< 20 ps	
fall time >2 ns)				
Ramp Wave Characteristics				
Frequency Range	1 μH to 10 MHz		1 μH to 15 MHz	
Linearity (<10 KHz, 1 V <sub>p-p</sub> , 100 %)	≤ 0.1 %		≤ 0.1%	
Symmetry	0 % to 100 %		0 % to 100 %	

 $<sup>^{2)}</sup>$  Amplitudes double on HiZ load  $^{3)}$  excluding  $f_{Sa}\text{-}F_{out},\,f_{Sa}\text{-}2\text{*}f_{out}$ 

	T3AWG3252	T3AWG3352	
Other Waves Characteristics			
Frequency Range			
Exponential Rise, Exponential Decay	1 μH to 10 MHz	1 μH to 15 MHz	
Sin(x)/x, Gaussian, Lorentz, Haversine	1 μH to 20 MHz	1 μH to 30 MHz	
Frequency Resolution			
Sin(x)/x	1 μH or 15 digits	1 μH or 15 digits	
Gaussian, Lorentz, Exponential Rise, Exponential Decay, Haversine	1 μH or 14 digits	1 μH or 14 digits	
Additive Noise			
Bandwitdh (-3 dB)	> 200 MHz	> 200 MHz	
Level	0 V to 6 V-   carrier max value(V <sub>pk</sub> )	0 V to 6 V-   carrier max value(V <sub>pk</sub> )	
Resolution	1 mV	1 mV	
Arbitrary			
Number of Samples	2 to 16.384	2 to 16.384	
Rise/Fall Time	2.0 ns	2.0 ns	
Jitter (rms)	< 20 ps	< 20 ps	
Frequency Range	1 μH to 125 MHz	1 μH to 150 MHz	
Frequency Resolution	1 μH or 15 digits	1 μH or 15 digits	
Frequency Accuracy			
Non-Arbitrary	± 2 % x 10 <sup>-6</sup> of setting		
Arbitrary	$\pm 2\% \times 10^{-6}$ of setting $\pm 1 \mu H$		

#### **Modulations**

	T3AWG3252	T3AWG3352
		·
AM (Ampitlude Modulation)		
Carrier Waveforms	Standard Waveforms (except Pul	se, DC and Noise) and Arbitrary
Modulation Source	Internal or External	
Internal Modulating Waveforms	Sine, Square, Ramp, Noise, Arbitr	ary
Modulating Frequency		
Internal	500 μHz to 48 MHz	
External	max 8 MHz	
Depth	0.00 % to 120.00 %	
FM (Frequency Modulation)		
Carrier Waveforms	Standard Waveforms (except Pul	se, DC and Noise) and Arbitrary
Modulation Source	Internal or External	
Internal Modulating Waveforms	Sine, Square, Ramp, Noise, Arbitr	ary
Modulating Frequency		
Internal	500 μHz to 48 MHz	
External	max 8 MHz	
Depth	0.00 % to 120.00 %	
Peak Deviation	DC to 250 MHz	DC to 350 MHz

	T3AWG3252	T3AWG3352
PM (Pulse Modulation)		
Carrier Waveforms	Standard Waveforms (except Pulse, DC and	d Noise) and Arbitrary
Modulation Source	Internal or External	
Internal Modulating Waveforms	Sine, Square, Ramp, Noise, Arbitrary	
Modulating Frequency		
Internal	500 µHz to 48 MHz	
External	max 8 MHz	
Peak Deviation Range	0° to 360°	
FSK (Frequency Shift Keying)		
Carrier Waveforms	Standard Waveforms (except Pulse, DC and	d Noise) and Arbitrary
Modulation Source	Internal or External	
Internal Modulating Waveforms	Square	
FSK Key Rate		
Internal	500 μHz to 48 MHz	
External	max 8 MHz	
Depth	0.00 % to 120.00 %	
Hop Frequency	1 μHz to 250 MHz	1 μHz to 350 MHz
Number of keys	2	
PSK (Phase Shift Keying)		
Carrier Waveforms	Standard Waveforms (except Pulse, DC and	d Noise) and Arbitrary
Modulation Source	Internal or External	
Internal Modulating Waveforms	Square	
PSK Key Rate		
Internal	500 μHz to 48 MHz	
External	max 8 MHz	
Depth	0.00 % to 120.00 %	
Hop Phase	0° to +360°	
Number of keys	2	
PWM (Pulse Width Modulation )		
Carrier Waveforms	Pulse	
Modulation Source	Internal or External	
Internal Modulating Waveforms	Sine, Square, Ramp, Noise, Arbitrary	
PSK Key Rate		
Internal	500 μHz to 48 MHz	
External	max 8 MHz	
Deviation Range	0 % to 50 % of pulse period	
PWM (Pulse Width Modulation )		
Carrier Waveforms	Pulse	
Modulation Source	Internal or External	
Internal Modulating Waveforms	Sine, Square, Ramp, Noise, Arbitrary	
PSK Key Rate		
Internal	500 μHz to 48 MHz	
External	max 8 MHz	
Deviation Range	0 % to 50 % of pulse period	

	T3AWG3252	T3AWG3352		
Sweep				
Туре	Linear, Logarithmic, Staircase and user defined			
Waveforms	Standard Waveforms (except Pulse, DC and No	pise) and Arbitrary		
Sweep Time	40 ns to 2000 s			
Hold/Return Times	0 to (2000 s-40 ns)			
Sweep/Hold/Return Time Resolution	20 ns or 12 digits	20 ns or 12 digits		
Total sweep time accuracy	≤ 0.4 %			
Start/Stop Frequency Range				
Sine	1 μHz to 250 MHz	1 μHz to 350 MHz		
Square	1 μHz to 120 MHz	1 μHz to 150 MHz		
Trigger Source	Internal/External/Manual			
Burst				
Туре	Trigger and Gated			
Waveforms	Standard Waveforms (except Pulse, DC and Noise) and Arbitrary			
Burst Count	1 to 4,294,967,295 cycles or infinite			

### AWG Specifications Variable Clock (True Arbitrary) Operating Mode

	T3AWG3252	T3AWG3352		
Sweep				
Ouput Channels				
Connectors	BNC on front panel			
Output Type	Single-ended DC coupled			
Output Impedance	$50~\Omega$ or $5\Omega$ (Low Impedance) selectable			
General Specifications				
Technology	Variable Clock (True Arbitrary)			
Run Modes	Continuous, Triggered Continuous, Single/Bu	rst, Stepped		
Vertical Resolution	16 bits			
Waveform Length	16 to 128 MSamples @Channel (up to 1 GSar	16 to 128 MSamples @Channel (up to 1 GSample @Channel)		
Waveform Granularity	1 (length > 384), 16 (16 $\leq$ length $\leq$ 384)			
Sequence Length	1 to 16384			
Sequence Repeat Counter	1 to 4,294,967,294 or infinite			
Timer				
Range	23.52 ns to 7 s			
Resolution	± 1 sampling clock cycle			
Analog Channel to Channel Skew				
Range	0 to 3.4 μs			
Resolution	≤ 5 ps			
Accuracy	±(1 %   setting   ± 20 ps)			
Initial Skew	< 200 ps			
Bandwidth calculated: (0.35 / rise or fall time)	318 MHz			

	T3AWG3252	T3AWG3352
Harmonic Distorsion Sine Wave 32 points, 1 V <sub>pp</sub>	< -60 dBc @(1 GS/s and 31.25 MHz)	< -60 dBc @(1.2 GS/s and 37.5 MHz)
<b>Spurious</b> Sine Wave 32 points, 1 V <sub>pp</sub>	< -60 dBc @(1 GS/s and 31.25 MHz)	< -60 dBc @(1.2 GS/s and 37.5 MHz)
SFDR (Spuriuos Free Dynamic Range) Sine Wave 32 points, 1 V <sub>pp</sub>	< -60 dBc @(1 GS/s and 31.25 MHz)	< -60 dBc @(1.2 GS/s and 37.5 MHz)
Rise/Fall Time 1 V <sub>pp</sub> , single-ended 10 % to 90 %	≤ 1.1 ns	≤ 1.1 ns
Overshoot 1 V <sub>pp</sub> , single-ended	< 2 %	

#### **Time Base and Clock**

	T3AWG3252	T3AWG3352
Sampling Rate		
Range	1 S/s to 1 GS/s	1 S/s to 1.2 GS/s
Resolution	16 Hz	
Accuracy	± 2.0 x 10 <sup>-6</sup>	± 2.0 x 10 <sup>-6</sup>
R <sub>j</sub> on clock patter (rms)	< 10 ps	< 10 ps

### **Digital Outputs**

	T3AWG3252	T3AWG3352		
Output Channels	<u>'</u>			
Connectors	mini-SAS HD connector on re	ar panel (not standard pin-out)		
Number of connectors	1			
Number of Outputs	8 channels	8 channels		
Output Impedance	100 Ω Differential	100 Ω Differential		
Output type	LVDS			
Rise/Fall time (10 % to 90 %)	< 1 ns			
Jitter (rms)	20 ps			
Maximum Update Rate	1 GS/s	1.2 GS/s		
Memory Depth	128 MSample @ Ch (up to 1 0	Sample)		

### Auxiliary input and output characteristics

	T3AWG3252	T3AWG3352
Marker Output		
connector type	BNC on Front panel	
Number of connectors	one	
Output impedance	50 Ω	
Output level (into 50 Ω)		
Amplitude	1 V to 2.5 V	
Resolution	10 mV	
Accuracy	± (2 % setting + 10 mV)	
Rise/Fall Ttime (10 % to 90 %, 2.5 V <sub>pp</sub> )	< 700 ps	
Jitter (rms)	20 ps	
Marker out to analog channel skew		
Range	Variable Clock Mode: 0 to 3 µs AFG Mode: 0 to 14 s. in continuos mode, 0 to 3	B µs in Trig. Mode
Resolution	Variable Clock Mode: 78 ps, AFG Mode: 39 ps	
Accuracy	± (1 % setting + 140 ps)	
Initial skew	< 1 ns	
Trigger/Gate Input		
Connector type	BNC on the Front Panel	
Input impedance	50 Ω / 1 ΚΩ	
Slope/Polarity	Positive or Negative or both	
Input damage level	< -15 V or > +15 V	
Threeshold control level	- 10 V to 10 V	
Resolution	50 mV	
Threshold control accuracy	±(10 %   setting   + 0.2 V)	
Input voltage swing	0.5 V <sub>p-p</sub> minimum	
Minimum pulse width (1 V <sub>pp</sub> )	3 ns	.00
Initial trigger/gate delay to Analog Output	Variable Clock Mode: < 240 * DAC clock period AFG Mode: < 360 ns (< 420 ns in troggeed swe	
Trigger in to output jitter	AFG Mode: < 40 ps Variable Clock Mode: 0.29 * DAC clock period	
Maximum frequency	AFG: 65 Mpts on Rising/Falling Edge, 80 MTps Variable Clock Mode: 42.5 MTps MTps = Mega Transition per second	on both edges
Reference clock input		
Connector type	SMA on rear panel	
Input impedance	50 Ω AC coupled	
Input Voltage range	·	e T10-90 < 1 ns and duty cycle from 40 % to 60 %)
Damage level	+14 dBm	
Frequency range	5 MHz to 100 MHz	
Reference clock output	0 WHZ to 100 WHZ	
Connector type	SMA on rear panel	
Output impedance	50 Ω AC coupled	_
	·	
Frequency range	10 MHz	
Accuracy	± 2.0 x 10-6	
Aging	± 1.0 x 10-6/year	
Amplitude	1.65 V	
Jitter (rms)	< 20 ps	

	T3AWG3252	T3AWG3352		
External modulation Input				
Connector type	SMA on rear panel			
Input impedance	> 2 MΩ			
Number of inputs	One			
Input Voltage Range	-0,5 V to +0.5 V			
Bandwidth	8 MHz with 40 MS/s sampling rate	8 MHz with 40 MS/s sampling rate		
Vertical resolution	8 bits			
Power				
Source Voltage and Frequency	100 to 240 VAC ±10 % @ 45-66 Hz			
Max Power Consumption	100 W	100 W		
Enviromental Characteristics				
Temperature (operating)	+5 °C to +40 °C (+41 °F to 104 °F)			
Temperature (non operating)	-20 °C to +60 °C (-4 °F to 140 °F)	-20 °C to +60 °C (-4 °F to 140 °F)		
Humidity (operating)	5 % to 80 % relative humidity with a maximum wet bulb temperature of 29 °C at or below +40 °C, (upper limit de-rates to 20.6 % relative humidity at +40 °C. Non-condensing.			
Humidity (non-operating)	5 % to 95 % relative humidity with a maximum wet bulb temperature of 40 °C at or below +60 °C, (upper limit de-rates to 29.8 % relative humidity at +60 °C. Non-condensing.			
Altitude (operating)	3,000 meters (9,842 feet) maximum	3,000 meters (9,842 feet) maximum at or below 25 °C		
Altitude (non operating)	12,000 meters (39,370 feet) maximu	12,000 meters (39,370 feet) maximum		
EMC and safety				
Safety	EN61010-1			
Main Standards	EN 61326-1:2013 – Electrical equipi EMC requirements – Part 1: General	ment for measurement, control and laboratory use – I requirements		
Immunity	EN 61326-1:2013			

### **System specifications**

	T3AWG3252 T3AWG3352		
Display	7 inch, 1024 x 600, capacitive touch LCD		
Operative System	Windows 10 IoT – LTSB (Long Term Service Branch)		
External Dimensions	W 362 mm - H 143 mm - D 258 mm		
Weight	6.5 kg		
Front panel connectors	CH1 OUTPUT (BNC)		
	CH2 OUTPUT (BNC)		
	MARKER OUT (BNC)		
	TRIGGER IN (BNC)		
Rear panel connectors	Ref. Clk. IN (SMA)		
	Ref. Clk. Out (SMA)		
	Ext. Mod. IN (SMA)		
	External monitor ports (HDMI, VGA or more)		
	DIGITAL POD A[70]		
	1x USB 2.0 and 1x USB 3.0 or more		
	Ethernet port (10/100/1000BaseT Ethernet, RJ45 port)		
	2 PS/2 keyboard and mouse ports		
Hard Disk	240 GB SSD or better		
Processor	Intel® Celeron J1900, 2 GHz (or better)		
Processor Memory	8 GB or better		

## T3AWG3-8DIG-TTL LVDS to LVTTL adapter

(Requires T3AWG3-8DIG and T3AWG3-8DIG-MSCAB)



	T3AWG3252	T3AWG3352		
Output Connector	20 position 2.54 mm 2 Row IDC H	20 position 2.54 mm 2 Row IDC Header		
Output Type	LVTTL			
Output Impedance	50 Ω nominal			
Output voltage	0.8 V to 3.8 V programmable in g	0.8 V to 3.8 V programmable in group og 8 bits		
Maximum update rate	125 Mbps@0.8 V and 400 Mbps@	@3.6 V		
Dimension	W 52 mm - H 22 mm - D 76 mm	n		
Input connectors	proprietary standard			
Cable length	1 meter			
Cable type	proprietary standard			

### T3AWG3-8DIG-SMA Mini-SAS HD to 16x SMA cable (8 LVDS outputs)

(Requires T3AWG3-8DIG)



	T3AWG3252	T3AWG3352
Output Connector	SMA	
Output Type	LVDS	
Number of SMA	16 (8 bits)	
Cable length	1 meter	
Cable type	proprietary standard	

#### **Ordering information**

Product Description	Product Code
Arbitrary Waveform Generator, 2 Ch, 250 MHz, 16 bit, 128 Mpts/Ch, 6 Vpp output, AFG/AWG,	T3AWG3252
Wave Sequencing	
Arbitrary Waveform Generator, 2 Ch, 350 MHz,16 bit, 128 Mpts/Ch, 6 Vpp output, AFG/AWG,	T3AWG3352
Wave Sequencing	
256 Mpt/Ch Memory Option for T3AWG3K-C	T3AWG3-M
512 Mpt/Ch Memory Option for T3AWG3K-C	T3AWG3-X
1024 Mpt/Ch Memory Option for T3AWG3K-C	T3AWG3-XL
High Voltage (12 V <sub>pp</sub> on 50 Ohm) for T3AWG3K-C	T3AWG3-HV
Digital 8 Ch. Output (Requires Mini-SAS cable)	T3AWG3-8DIG
LVDS to LVTTL adapter. (Requires T3AWG3-8DIG and T3AWG3-8DIG-MSCAB)	T3AWG3-8DIG-TTL
Mini-SAS HD to 16x SMA cable (8 LVDS output). (Requires T3AWG3-8DIG)	T3AWG3-8DIG-SMA
3U - 19" RACKMOUNT KIT for T3AWG3K-C	T3AWG3-RACKMOUNT
Warranty extended to 3 Years	T3AWG3-W3
Cable Mini SAS HD 1m for 8-DIG. (Requires T3AWG3-8DIG)	T3AWG3-8DIG-MSCAB

Standard warranty is one year.

### **ABOUT TELEDYNE TEST TOOLS**



#### **Company Profile**

Teledyne LeCroy is a leading provider of oscilloscopes, protocol analyzers and related test and measurement solutions that enable companies across a wide range of industries to design and test electronic devices of all types. Since our founding in 1964, we have focused on creating products that improve productivity by helping engineers resolve design issues faster and more effectively. Oscilloscopes are tools used by designers and engineers to measure and analyze complex electronic signals in order to develop high-performance systems and to validate electronic designs in order to improve time to market.

The Teledyne Test Tools brand extends the Teledyne LeCroy product portfolio with a comprehensive range of test equipment solutions. This new range of products delivers a broad range of quality test solutions that enable engineers to rapidly validate product and design and reduce time-to-market. Designers, engineers and educators rely on Teledyne Test Tools solutions to meet their most challenging needs for testing, education and electronics validation.

#### **Location and Facilities**

Headquartered in Chestnut Ridge, New York, Teledyne Test Tools and Teledyne LeCroy has sales, service and development subsidiaries in the US and throughout Europe and Asia. Teledyne Test Tools and Teledyne LeCroy products are employed across a wide variety of industries, including semiconductor, computer, consumer electronics, education, military/aerospace, automotive/industrial, and telecommunications.

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